



## 4.8 V NPN Common Emitter Output Power Transistor for GSM Class IV Phones

### Technical Data

### AT-36408

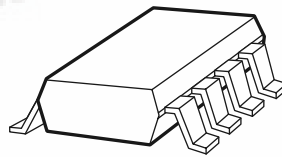
#### Features

- 4.8 Volt Pulsed Operation (pulse width = 577  $\mu$ sec, duty cycle = 12.5%)
- +35.0 dBm  $P_{out}$  @ 900 MHz, Typ.
- 65% Collector Efficiency @ 900 MHz, Typ.
- 9 dB Power Gain @ 900 MHz, Typ.
- Internal Input Pre-Matching Facilitates Cascading

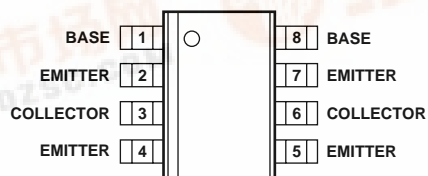
#### Applications

- Output Power Device for GSM Class IV Handsets

#### SOIC-8 Surface Mount Plastic Package Outline P8



#### Pin Configuration



#### Description

Hewlett Packard's AT-36408 combines internal input pre-matching with low cost, NPN power silicon bipolar junction transistors in a SOIC-8 surface mount plastic package. This device is designed for use as the output device for GSM Class IV handsets. At 4.8 volts, the device features +35 dBm pulsed output power, superior power added efficiency, and excellent gain, making the AT-36408 an excellent choice for battery powered systems.

The AT-36408 is fabricated with Hewlett Packard's 10 GHz  $F_t$  Self-Aligned-Transistor (SAT) process. The die are nitride passivated for surface protection. Excellent device uniformity, performance and reliability are produced by the use of ion-implantation, self-alignment techniques, and gold metalization in the fabrication of these devices.

## AT-36408 Absolute Maximum Ratings

Symbol	Parameter	Units	Absolute Maximum <sup>[1]</sup>
$V_{EBO}$	Emitter-Base Voltage	V	1.4
$V_{CBO}$	Collector-Base Voltage	V	16.0
$V_{CEO}$	Collector-Emitter Voltage	V	9.5
$I_C$	Collector Current <sup>[2]</sup>	A	1.7
$P_T$	Peak Power Dissipation <sup>[2, 3]</sup>	W	8.6
$T_j$	Junction Temperature	°C	150
$T_{STG}$	Storage Temperature	°C	-65 to 150

**Thermal Resistance<sup>[4]</sup>:**

$$\theta_{jc} = 60^\circ\text{C/W}$$

### Notes:

1. Permanent damage may occur if any of these limits are exceeded.
2. Pulsed operation, pulse width = 577  $\mu\text{sec}$ , duty cycle = 12.5%.
3. Derate at 133.3 mW/°C for  $T_C > 85^\circ\text{C}$ .  $T_C$  is defined to be the temperature of the collector pins 3 and 6, where the lead contacts the circuit board.
4. Using the liquid crystal technique,  $V_{CE} = 4.5\text{ V}$ ,  $I_C = 100\text{ mA}$ ,  $T_j = 150^\circ\text{C}$ , 1-2  $\mu\text{m}$  "hot-spot" resolution.

## Electrical Specifications, $T_C = 25^\circ\text{C}$

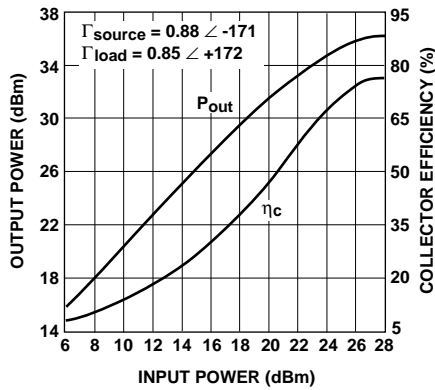
Symbol	Parameters and Test Conditions	Units	Min.	Typ.	Max.
	Freq. = 900 MHz, $V_{CE} = 4.8\text{ V}$ , $I_{CQ} = 50\text{ mA}$ , pulsed operation, pulse width = 577 $\mu\text{sec}$ , duty cycle = 12.5%, Test Circuit A, unless otherwise specified				
$P_{out}$	Output Power <sup>[1]</sup> $P_{in} = +26\text{ dBm}$	dBm	+34.0	+35.0	
$\eta_C$	Collector Efficiency <sup>[1]</sup> $P_{in} = +26\text{ dBm}$	%	55	65	
H2	2nd Harmonic <sup>[1]</sup> $F_0 = 900\text{ MHz}$	dBc		-50	
H3	3rd Harmonic <sup>[1]</sup> $F_0 = 900\text{ MHz}$	dBc		-40	
	Mismatch Tolerance, No Damage <sup>[1]</sup> $P_{out} = +35\text{ dBm}$ any phase, 2 sec duration				7:1
$BV_{EBO}$	Emitter-Base Breakdown Voltage $I_E = 0.8\text{ mA}$ , open collector	V	1.4		
$BV_{CBO}$	Collector-Base Breakdown Voltage $I_C = 4.0\text{ mA}$ , open emitter	V	16.0		
$BV_{CEO}$	Collector-Emitter Breakdown Voltage $I_C = 20.0\text{ mA}$ , open base	V	9.5		
$h_{FE}$	Forward Current Transfer Ratio $V_{CE} = 3\text{ V}$ , $I_C = 180\text{ mA}$	—	80	150	330
$I_{CEO}$	Collector Leakage Current $V_{CEO} = 5\text{ V}$	$\mu\text{A}$			50

### Note:

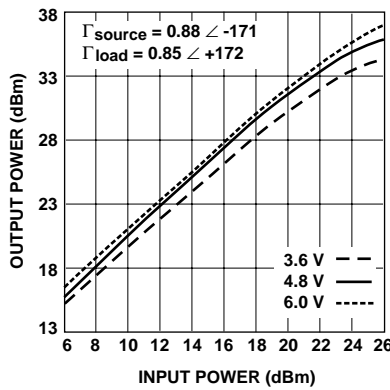
1. With external matching on input and output, tested in a 50 ohm environment. Refer to Test Circuit A (GSM).

## AT-36408 Typical Performance, $T_C = 25^\circ\text{C}$

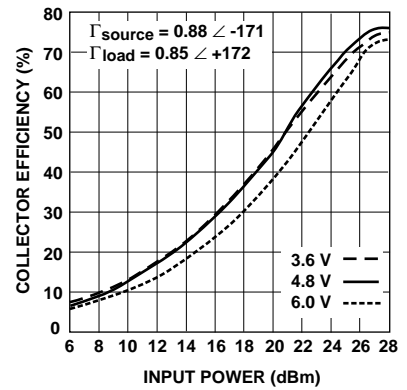
Frequency = 900 MHz,  $V_{CE} = 4.8\text{ V}$ ,  $I_{CQ} = 50\text{ mA}$ , pulsed operation, pulse width = 577  $\mu\text{sec}$ , duty cycle = 12.5%, Test Circuit A (GSM), unless otherwise specified.



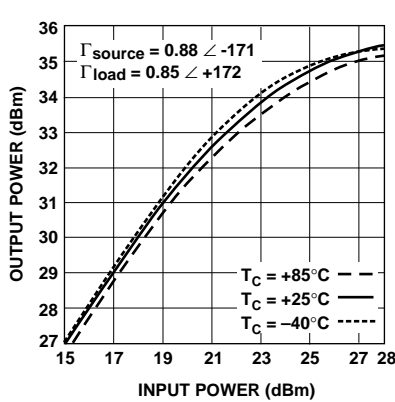
**Figure 1. Output Power and Collector Efficiency vs. Input Power.**



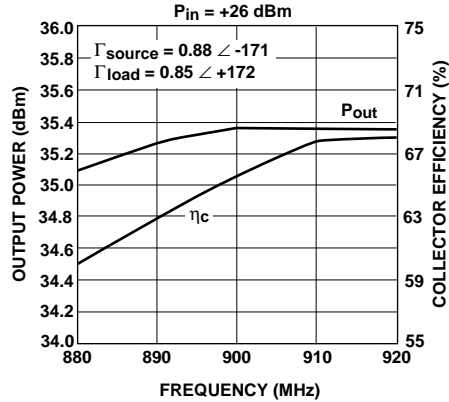
**Figure 2. Output Power vs. Input Power Over Bias Voltage.**



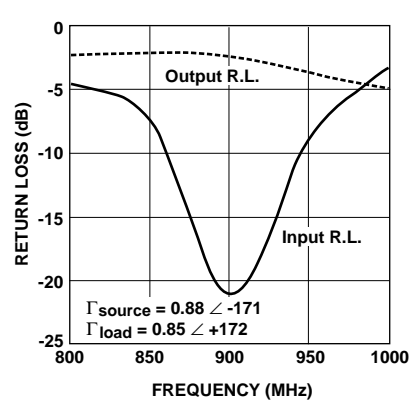
**Figure 3. Collector Efficiency vs. Input Power Over Bias Voltage.**



**Figure 4. Output Power vs. Input Power Over Temperature.**



**Figure 5. Output Power and Collector Efficiency vs. Frequency.**  
Note: Tuned at 900 MHz, then swept over frequency.



**Figure 6. Input and Output Return Loss vs. Frequency.**

## AT-36408 Typical Large Signal Impedances

$V_{CE} = 4.8\text{ V}$ ,  $I_{CQ} = 50\text{ mA}$ , Pulsed Operation,  $P_{out} = +35.0\text{ dBm}$

Freq. MHz	$\Gamma_{source}$		$\Gamma_{load}$	
	Mag.	Ang.	Mag.	Ang.
880	0.882	-170.0	0.847	172.7
890	0.885	-170.5	0.849	172.2
900	0.887	-171.1	0.851	171.6
910	0.890	-171.4	0.853	171.1
915	0.891	-169.0	0.854	168.4
920	0.893	-168.4	0.855	168.2

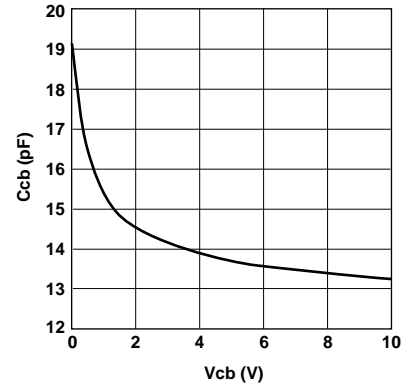
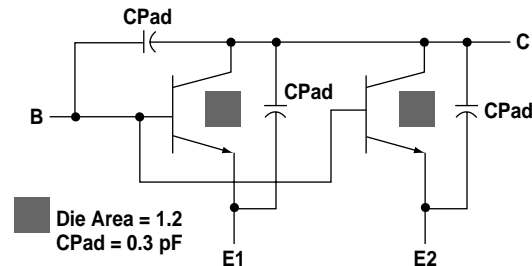


Figure 7. Collector-Base Capacitance vs. Collector-Base Voltage (DC Test).

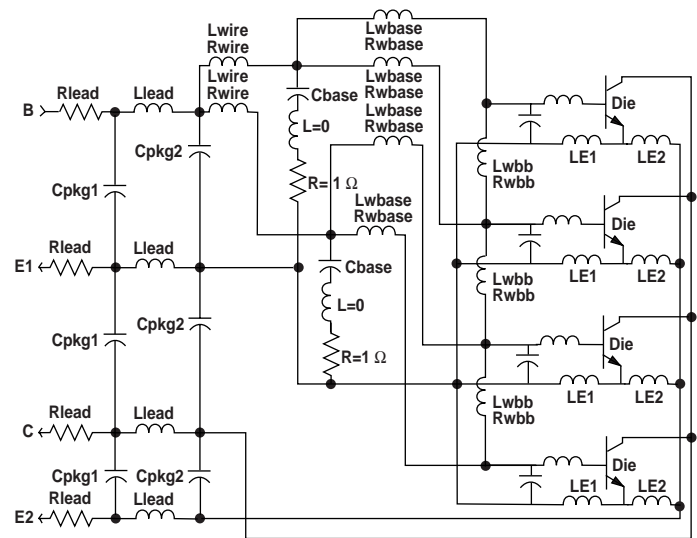
## SPICE Model Parameters

### Die Model



Label	Value	Label	Value
BF	280	TR	1E-9
IKF	299.9	EG	1.11
ISE	9.9E-11	IS	3.598E-15
NE	2.399	XTI	3
VAF	33.16	CJC	0.8E-12
NF	0.9935	VJC	0.4831
TF	1.6E-11	MJC	0.2508
XTF	0.006656	XCJC	0.001
VTF	0.02785	FC	0.999
ITF	0.001	CJE	6.16E-12
PTF	23	VJE	1.186
XTB	0	MJE	0.5965
BR	54.61	RB	0.752
IKR	81	IRB	0
ISC	8.7E-13	RBM	0.01
NC	1.587	RE	1.27
VAR	1.511	RC	0.107
NR	0.9886		

### Packaged Model



Label	Value	Label	Value
Rlead	0.63 $\Omega$	LE2	0.00064 nH
Llead	1.45 nH	Cbase	46.0 pF
Rwire	1.3 $\Omega$	Rwbase	0.2 $\Omega$
Lwire	0.52 nH	Lwbase	1.19 nH
Cpkg1	0.4 pF	Rwbb	0.1 $\Omega$
Cpkg2	1.2 pF	Lwbb	0.1 nH
LE1	0.3 nH		

## AT-36408 Typical Scattering Parameters, Common Emitter, $Z_0 = 50 \Omega$

$V_{CE} = 3.6 \text{ V}, I_c = 200 \text{ mA}, T_c = 25^\circ\text{C}$

Freq. GHz	$S_{11}$		dB	$S_{21}$		dB	$S_{12}$		$S_{22}$	
	Mag.	Ang.		Mag.	Ang.		Mag.	Ang.	Mag.	Ang.
0.05	0.96	-175	22.3	13.08	93	-38.4	0.012	11	0.74	-169
0.10	0.96	-178	16.4	6.61	88	-37.7	0.013	13	0.74	-174
0.25	0.96	177	8.8	2.76	80	-36.5	0.015	24	0.75	-177
0.50	0.94	173	4.2	1.63	66	-34.4	0.019	33	0.73	-177
0.75	0.90	169	3.4	1.49	46	-32.0	0.025	27	0.71	-172
0.90	0.84	168	4.2	1.63	24	-32.0	0.025	10	0.72	-165
1.00	0.79	170	4.6	1.70	0	-34.0	0.020	-14	0.81	-160
1.25	0.92	175	-1.2	0.87	-68	-37.1	0.014	126	1.01	-172
1.50	0.97	169	-9.6	0.33	-98	-30.2	0.031	97	0.96	-177

$V_{CE} = 4.8 \text{ V}, I_c = 200 \text{ mA}, T_c = 25^\circ\text{C}$

0.05	0.96	-174	22.6	13.42	93	-37.7	0.013	11	0.74	-169
0.10	0.96	-178	16.6	6.79	88	-37.7	0.013	13	0.73	-174
0.25	0.96	178	9.0	2.83	80	-36.5	0.015	23	0.74	-177
0.50	0.94	173	4.4	1.66	66	-34.4	0.019	32	0.72	-176
0.75	0.90	169	3.6	1.51	46	-32.4	0.024	26	0.70	-172
0.90	0.84	168	4.3	1.64	24	-32.0	0.025	9	0.72	-164
1.00	0.80	170	4.6	1.71	0	-34.0	0.020	-14	0.81	-160
1.25	0.92	175	-1.0	0.89	-67	-37.1	0.014	126	1.01	-171
1.50	0.97	169	-9.4	0.34	-97	-30.2	0.031	97	0.96	-177

$V_{CE} = 6.0 \text{ V}, I_c = 200 \text{ mA}, T_c = 25^\circ\text{C}$

0.05	0.96	-174	22.7	13.60	93	-37.7	0.013	12	0.73	-169
0.10	0.96	-178	16.7	6.88	88	-37.1	0.014	14	0.72	-174
0.25	0.96	178	9.2	2.87	79	-35.9	0.016	23	0.73	-177
0.50	0.94	173	4.5	1.68	65	-34.0	0.020	30	0.71	-176
0.75	0.90	169	3.7	1.52	45	-32.0	0.025	24	0.69	-171
0.90	0.85	168	4.3	1.64	23	-32.0	0.025	8	0.72	-164
1.00	0.80	170	4.6	1.70	0	-34.0	0.020	-14	0.81	-159
1.25	0.92	175	-1.0	0.90	-67	-37.7	0.013	125	1.01	-171
1.50	0.97	169	-9.2	0.35	-97	-30.2	0.031	96	0.95	-177

## Typical Performance

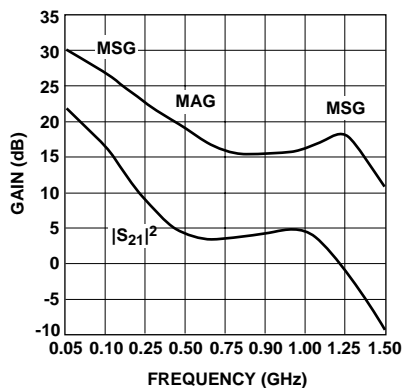


Figure 8. Insertion Power Gain, Maximum Available Gain, and Maximum Stable Gain vs. Frequency.  $V_{CE} = 3.6 \text{ V}, I_c = 200 \text{ mA}$ .

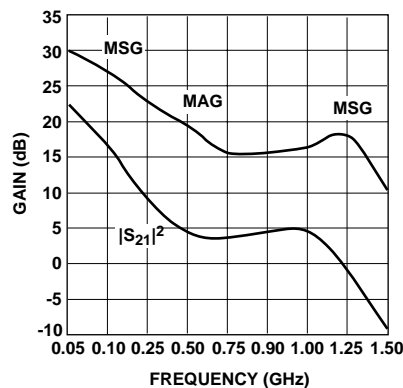


Figure 9. Insertion Power Gain, Maximum Available Gain, and Maximum Stable Gain vs. Frequency.  $V_{CE} = 4.8 \text{ V}, I_c = 200 \text{ mA}$ .

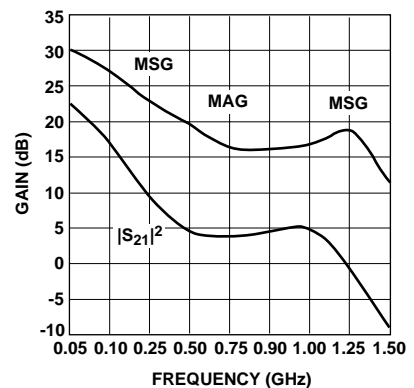
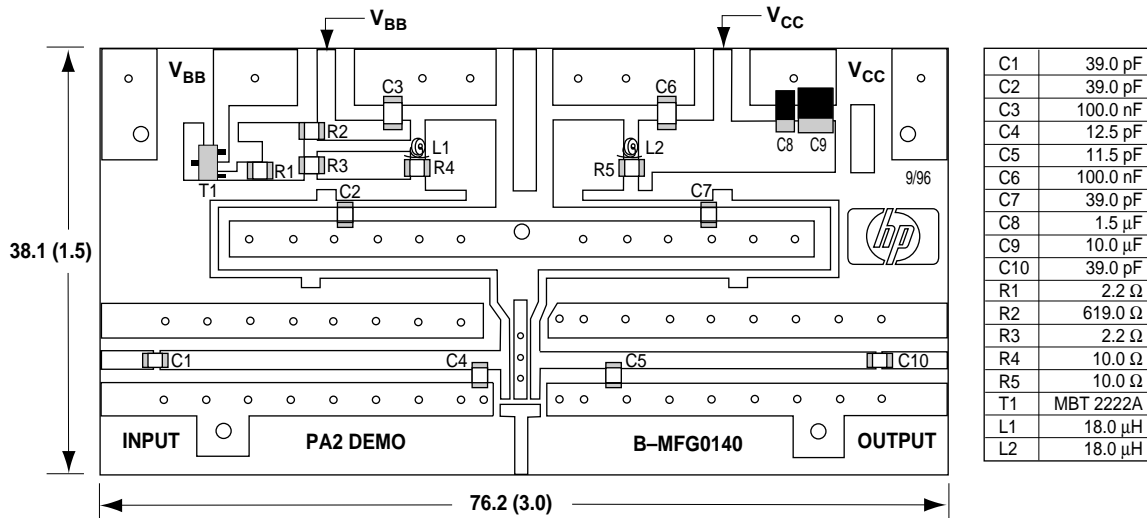


Figure 10. Insertion Power Gain, Maximum Available Gain, and Maximum Stable Gain vs. Frequency.  $V_{CE} = 6.0 \text{ V}, I_c = 200 \text{ mA}$ .

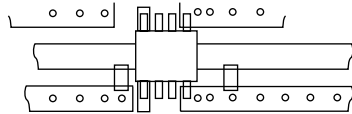
### Test Circuit A: Test Circuit Board Layout @ 900 MHz (GSM)



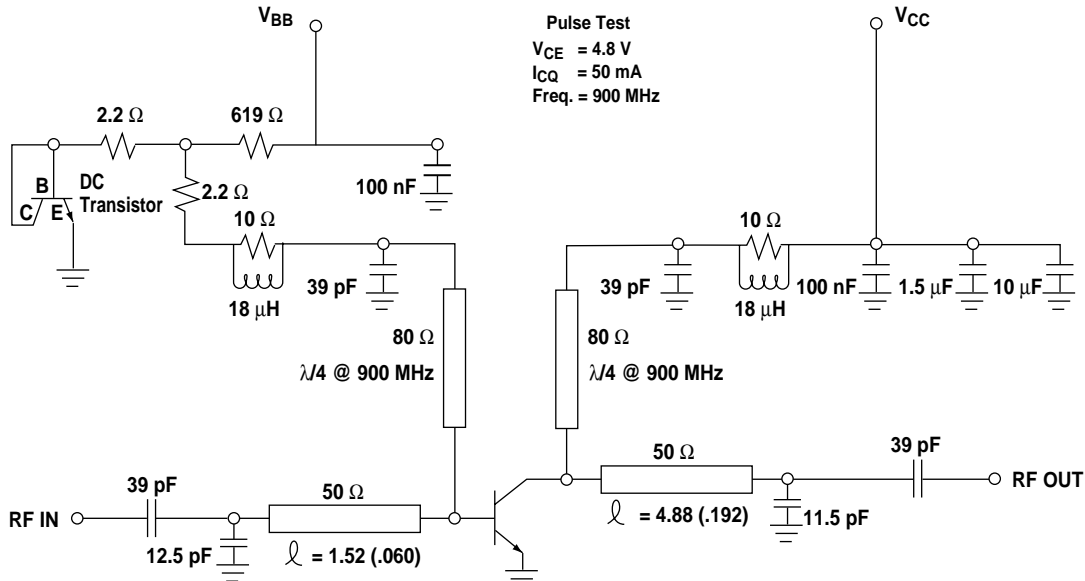
**Pulse Test**  
 $V_{CE} = 4.8 \text{ V}$   
 $I_{CQ} = 50 \text{ mA}$   
 Freq. = 900 MHz

**Test Circuit:**  
 FR-4 Microstrip, glass epoxy board  
 Dielectric Constant = 4.5  
 Thickness = 0.79 (.031)

**NOTE:**  
 Dimensions are shown in millimeters (inches).



### Test Circuit A: Test Circuit Schematic Diagram @ 900 MHz (GSM)

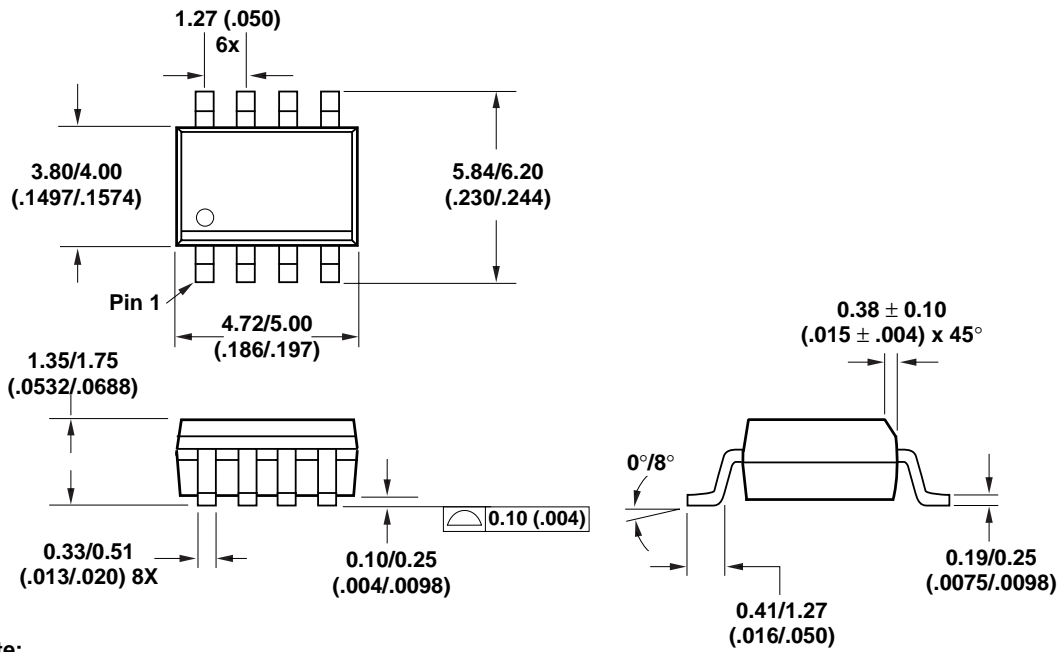


## Part Number Ordering Information

Part Number	No. of Devices	Container
AT-36408-TR1	1000	7" Reel
AT-36408-BLK	25	Carrier Tape

## Package Dimensions

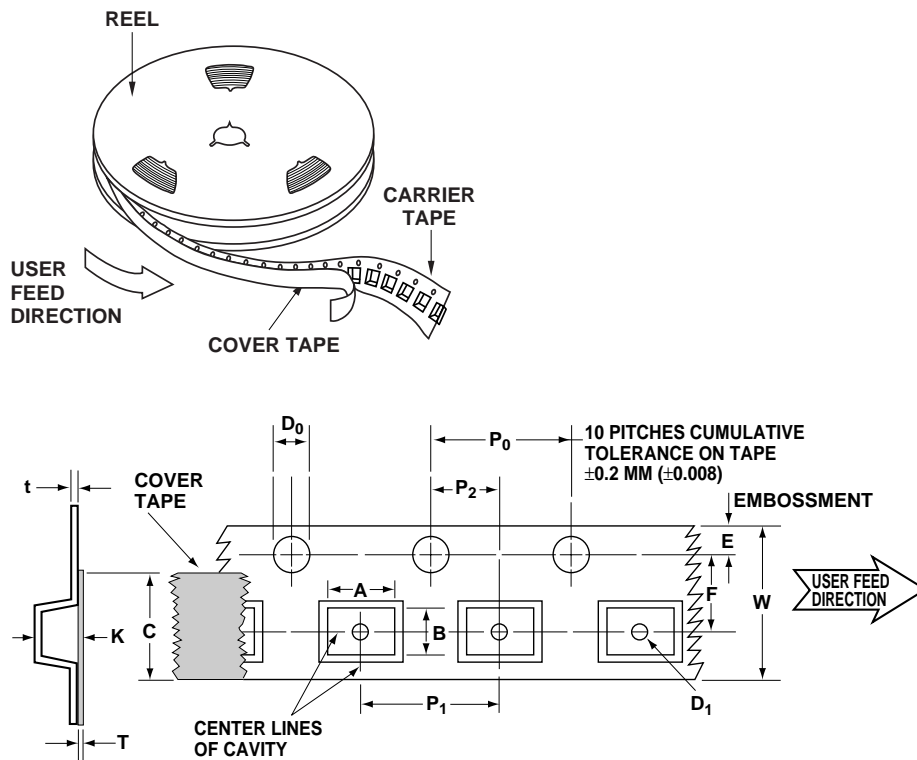
### SOIC-8 Surface Mount Plastic Package



#### Note:

- Dimensions are shown in millimeters (inches).

## Tape Dimensions and Product Orientation For Package SOIC-8



	DESCRIPTION	SYMBOL	SIZE (mm)	SIZE (INCHES)
CAVITY	LENGTH	A	$6.45 \pm 0.10$	$0.254 \pm 0.004$
	WIDTH	B	$5.13 \pm 0.10$	$0.202 \pm 0.004$
	DEPTH	K	$2.11 \pm 0.10$	$0.083 \pm 0.004$
	PITCH	$P_1$	$8.00 \pm 0.10$	$0.315 \pm 0.004$
	BOTTOM HOLE DIAMETER	$D_1$	1.50 min.	0.059 min.
PERFORATION	DIAMETER	$D_0$	$1.50 + 0.10/-0$	$0.059 + 0.004/-0$
	PITCH	$P_0$	$4.00 \pm 0.10$	$0.157 \pm 0.004$
	POSITION	E	$1.75 \pm 0.10$	$0.069 \pm 0.004$
CARRIER TAPE	WIDTH	W	$8.00 \pm 0.30$	$0.315 \pm 0.012$
	THICKNESS	t	$0.255 \pm 0.013$	$0.0100 \pm 0.0005$
COVER TAPE	WIDTH	C	$9.19 \pm 0.10$	$0.362 \pm 0.004$
	TAPE THICKNESS	T	$0.051 \pm 0.010$	$0.0020 \pm 0.0004$
DISTANCE BETWEEN CENTERLINE	CAVITY TO PERFORATION (WIDTH DIRECTION)	F	$5.51 \pm 0.05$	$0.217 \pm 0.002$
	CAVITY TO PERFORATION (LENGTH DIRECTION)	$P_2$	$2.00 \pm 0.05$	$0.079 \pm 0.002$